



Docket No.: 49959-145

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of

: Response Under 37 CFR 1.116 - Expedited Procedure  
Customer Number: 20277

Daniel I SOME, et al.

: Confirmation Number: 3092

Serial No.: 09/784,626

: Group Art Unit: 2882 ✓

Filed: February 14, 2001

: Examiner: Hoon K. Song

For: LASER SCANNING WAFER INSPECTION USING NONLINEAR OPTICAL PHENOMENA

Box AFMail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Transmitted herewith is an Amendment in the above-identified application.

☐  
☐  
☐

No additional fee is required.

Applicant is entitled to small entity status under 37 CFR 1.27

Also attached:

The fee has been calculated as shown below:

	NO. OF CLAIMS	HIGHEST PREVIOUSLY PAID FOR	EXTRA CLAIMS	RATE	FEE
Total Claims	32	34	0	\$18.00 =	\$0.00
Independent Claims	4	3	1	\$86.00 =	\$86.00
Multiple claims newly presented					\$0.00
Fee for extension of time					\$0.00
Total of Above Calculations					\$86.00

☒ Please charge my Deposit Account No. 500417 in the amount of \$86.00. An additional copy of this transmittal sheet is submitted herewith.

☒ The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. 500417, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted;

MCDERMOTT, WILL & EMERY

*Michael A. Messina*

Michael A. Messina

Registration No. 33,424

600 13<sup>th</sup> Street, N.W.  
Washington, DC 20005-3096  
(202) 756-8000 MAM:mcm  
Facsimile: (202) 756-8087  
Date: November 7, 2003

RECEIVED  
NOV 14 2003  
TECHNOLOGY CENTER 2800



Docket No.: 49959-145

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : **RESPONSE UNDER 37 CFR 1.116**

Daniel I SOME, et al.

: **EXPEDITED PROCEDURE**

: Customer Number: 20277

Serial No.: 09/784,626

: Confirmation Number: 3092

Filed: February 14, 2001

: Group Art Unit: 2882

: Examiner: Hoon K. Song

For: **LASER SCANNING WAFER INSPECTION USING NONLINEAR OPTICAL  
PHENOMENA**

**AMENDMENT UNDER 37 CFR 1.116**

Mail Stop Not sure yet  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

RECEIVED  
NOV 14 2003  
TECHNOLOGY CENTER 2800

Sir:

The following Amendment and Remarks are submitted in response to the Final Office

Action mailed September 17, 2003. Please amend the above-identified application as follows.

11/10/2003 JBALINAM 00000032 500417 09784626

01 FC:1201

86.00 DA